SGLS093 - MARCH 1997

- Duty Cycle for LCD Driver is Over 1/400
- Recommended V_{EE} Voltage Range for LCD Driver: 20 V to 42 V (45 V Max)
- 160 Channel Outputs

- Power Supply Voltage . . . 5 V ± 10%
- High-Voltage CMOS SI Gate Technology
- TAB (Tape Automated Bonding) Packaging

description

The MPT57202 is a CMOS integrated circuit designed to drive an LCD (liquid crystal display) for a dot matrix STN (super twisted nematic). The outputs can be configured as one set of 160 output channels or as two sets of 80 output channels. The duty cycle is over 1/400, and the output bias voltage range (V_{EE}) is from 20 V to 42 V (45 V maximum).

The outputs can be configured as one set of 160 output channels or as 2 sets of 80 output channels. This high-voltage CMOS SI gate device is available in a custom TAB (tape automated bonding) package.

The MPT57202 is characterized for operation over the full military temperature range of -55°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SGLS093 – MARCH 1997

function table

SIGNAL	COMMON (ROW) MODE						
BS	Not Use	ed (tie low)					
D7-D0	Ni-cut-						
	Not Us	ed (tie low)					
DISP OFF [†]	TEST VL2	TEST VL2 (display off): L					
DST	Data shift o	on falling edge					
80 CH	L = 160-channel	H=80-channel x 2 (parallel)					
EIO1	Serial I/O	1 CH Serial I/O					
EIO2	See Note 1	80 CH Serial I/O					
EIO3	See Note 1	81 CH Serial I/O					
EIO4	Serial I/O	160 CH Serial I/O					
	L/R = L (left shift) EIO1 \leftarrow <r1> \leftarrow <r2> \leftarrow <r3>\leftarrow <r160> \leftarrow EIO4</r160></r3></r2></r1>						
Ī/R	L/R = H EIO1 $\rightarrow \langle R1 \rangle \rightarrow \langle R2 \rangle$ -	(right shift) → <r3>→ <r160> → EIO4</r160></r3>					
	M, data combination	Selects level					
М	0,1 VL1 1,0 VL3 0,0 VL4 1,1 VL2						
MODE		L					
SCK	Not use	ed (tie low)					
TEST	Test pin	= L or open					

[†]This terminal should be low at power up for logic resetting.

NOTE 1: This terminal is not used in this configuration. Although the pin produces a low output level, it should be left open.



SGLS093 - MARCH 1997



functional block diagram



SGLS093 - MARCH 1997

power supply circuit



NOTE A. Separation between high voltage GND (VSS1, VSS2) line and logic GND (VSS3) line is recommended to avoid noise problems.



schematics of inputs and outputs



SGLS093 - MARCH 1997

Terminal Functions

common (row) driver mode

TERMINAL NAME	I/O	DESCRIPTION
80CH	I	80CH is the 160-channel/80-channel mode select L = 160-channel data shift mode; H = 80-channel-x-2 data shift mode
BS	I	Not used (tie low)
D7-D0	I	Not used (tie low)
DISP OFF	I	Display off. A low level on DISP OFF disables normal operation, turning the display off (0V) and enabling the test mode. DISP OFF must be tied high for normal operation.
DST	I	Data strobe. DST is the data strobed input.
EIO1	I/O	Serial I/O 1. When \overline{L}/R is high, EIO1 is an active-high serial input. When \overline{L}/R is low (left-shift mode), EIO1 is an active-high serial output.
EIO2	I/O	Serial I/O 2: When the device is configured in 160-channel data shift mode (80CH = L), EIO2 is not used and should be left open. When the device is configured in 80-channel-×-2 data shift mode (80CH = H) and L/R is low; this EIO2 is an active-high serial input for the first 80-channel output section. L/R is high; EIO2 is an active-high serial output for the first 80-channel output section.
EIO3	I/O	Serial I/O 3: When MPT57202 is configured in 160-channel data shift mode (80 CH = L), EIO3 is not used and should be left open. When the device is configured in 80-channel-x-2 data shift mode (80CH = H) and L/R is low; EIO3 is an active-high serial output for the first 80-channel output section. L/R is high; EIO3 is an active-high serial input for the first 80-channel output section.
EIO4	I/O	Serial I/O 4: When $\overline{L}/R = H$: EIO4 is an active-high serial output When $L/R = L$: EIO4 is an active-high serial input
Ī/R	Ι	Select left or right shift When the MPT57202 is in 160-channel data shift mode (80CH = L) and $\overline{L}/R = H$, data is right shifted into EIO1 and out from EIO4 EIO1 \rightarrow <r1> \rightarrow <r2> \rightarrow <r3>\rightarrow <r160> \rightarrow EIO4 When the MPT57202 is in 160-channel data shift mode (80CH = L) and $\overline{L}/R = L$, data is left shifted into EIO4 and out from EIO1 EIO1 \leftarrow <r1> \leftarrow <r2> \leftarrow <r3>\leftarrow <r160> \leftarrow EIO4 When the MPT57202 is in 80-channel-\times-2 data shift mode with two parallel 80-channel output sections (80CH = H) and $\overline{L}/R = H$, data is right shifted into EIO1 and EIO3 and out from EIO2 and EIO4 EIO1 \rightarrow <r1> \rightarrow <r2> \rightarrow <r3>\rightarrow <r80> \rightarrow EIO2 EIO3 \rightarrow <r81> \rightarrow <r82> \rightarrow <r83>\rightarrow <r160> \rightarrow EIO4 When the MPT57202 is in 80-channel-\times-2 data shift mode with two parallel 80-channel output sections (80CH = H) and $\overline{L}/R = L$, data is right shifted into EIO2 and EIO4 When the MPT57202 is in 80-channel-\times-2 data shift mode with two parallel 80-channel output sections (80CH = H) and $\overline{L}/R = L$, data is left shifted into EIO2 and EIO4 and out from EIO1 and EIO3 EIO1 \leftarrow <r1> \leftarrow <r2> \leftarrow <r3>\leftarrow <r160> \leftarrow EIO4 In all cases, R<1> \rightarrow OUT1, e.g., R<1> \rightarrow OUT1, R<76> \rightarrow OUT76, etc. See Table 1 for the cascade configuration.</r160></r3></r2></r1></r160></r83></r82></r81></r80></r3></r2></r1></r160></r3></r2></r1></r160></r3></r2></r1>
M	I	Frame signal input
MODE	I	Common/segment mode select. MODE should be tied low.
OUT1-OUT160	0	Common (row) driver output channels (see Table 2)
SCK	1	Not used (tie low)



SGLS093 - MARCH 1997

Terminal Functions (continued)

TERMINAL NAME	I/O	DESCRIPTION
TEST	I	TEST is used for factory testing only. For normal operation tie TEST low or leave it open. TEST has an internal pulldown resistor.
VCC		5-V supply terminal
V _{EE1}		Output buffer bias
V _{EE2}		Output logic bias
VL1		VL1 is the on-level of the LCD driver output
VL2		VL2 is the off-level of the LCD driver output
VL3		VL3 is the on-level of the LCD driver output
VL4		VL4 is the off-level of the LCD driver output
V _{SS1}		Ground terminal with respect to V _{EE1}
V _{SS2}		Ground terminal with respect to V _{EE2}
V _{SS3}		Ground terminal with respect to V_{CC}

Table 1. Cascade Configurations - Common-Driver Mode (MODE = L)

INP	JTS		I/	0		NUMBER OF CHANNELS/
80 CH	Ī/R	EIO1	EIO2	EIO3	EIO4	SHIFT DIRECTION
L	Н	Input	-	-	Output	160/right
L	L	Output	-	-	Input	160/left
Н	Н	Input	Output	Input	Output	80 x 2/right
Н	L	Output	Input	Output	Input	80 x 2/left



SGLS093 - MARCH 1997

absolute maximum ratings over free-air temperature range[†]

Supply voltage range, V _{CC} (see Note 2)	0.3 V to 7 V
Input voltage range, V ₁ (DST, SCK, M, MODE, 80CH, L/R, BS, EIO1-EIO4,	-
D0-D7, DISP OFF, TEST)	-0.3 V to V _{CC} + 0.3 V
Output voltage range, V _O (EIO1, EIO2, EIO3, EIO4)	-0.3 V to V _{CC} + 0.3 V
Output bias voltage range for LCD (V _{EE1} , V _{EE2})	0.3 V to 45 V
Supply voltage range for LCD (VL1, VL2, VL3, VL4) (see Note 3)	-0.3 V to V _{EE} + 0.3 V
Input current, I ₁	±10 mA
Output current, I _{O:} EIO1 to EIO4	10 mA
OUT1 to OUT160	5 mA
Storage temperature range, T _{stg}	\ldots . –65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 2. Voltage values are with respect to V_{SS1}, V_{SS2}, and V_{SS3}.
 - 3. The following conditions must be met:

 $\begin{array}{l} \mathsf{V}_{EE1} \text{ and } \mathsf{V}_{EE2} \geq \mathsf{VL1} \geq \mathsf{VL3} \geq \mathsf{VEE} \text{ - 7 V, and 7 V} \geq \mathsf{VL4} \geq \mathsf{VL2} \geq \mathsf{V}_{SS1}, \mathsf{V}_{SS2}, \mathsf{V}_{SS3} \\ \mathsf{V}_{EE1} \text{ and } \mathsf{V}_{EE2} > \mathsf{VL1} > \mathsf{VL3} > \mathsf{V}_{EE} \text{ - } \Delta \text{ V, and } \Delta \text{ V} > \mathsf{VL4} > \mathsf{VL2} > \mathsf{V}_{SS1}, \mathsf{V}_{SS2}, \mathsf{V}_{SS3} \\ (\text{See Figure 1 for a graphic representation of } \Delta \text{ V}). \end{array}$



VEE – Output Bias Voltage Range – V





SGLS093 - MARCH 1997

recommended operating conditions (see Figure 2)

			MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	See Notes 4 and 5		4.5	5	5.5	V
Supply voltage, VSS				0		V
Supply voltage for LCD drive	See Notes 4 and 5	V _{EE1} , V _{EE2} , VL1, VL3, VL4, VL2	20		42	V
High-level input voltage, VIH		80CH, BS, D7–D0, <mark>DISP OFF</mark> , DST, EIO1-EIO4, L/R, M, MODE, SCK, TEST	0.8 V _{CC}		VCC	V
Low-level input voltage, VIL		80CH, BS, D7–D0, <mark>DISP OFF</mark> , DST, EIO1-EIO4, L/R, M, MODE, SCK, TEST	V _{SS}		0.2 V _{CC}	V
Clock frequency, f _{CLK}		DST			1	MHz
Operating free-air temperature, T _A			-55		125	°C

NOTES: 4. VLn voltage range should be under the following conditions:

 $\begin{array}{l} \mathsf{V}_{EE1} \text{ and } \mathsf{V}_{EE2} \geq \mathsf{VL1} \geq \mathsf{VL3} \geq \mathsf{V}_{EE} \text{ - 7 V, and 7 V} \geq \mathsf{VL4} \geq \mathsf{VL2} \geq \mathsf{V}_{SS1}, \mathsf{V}_{SS2} \mathsf{V}_{SS3} \\ \mathsf{V}_{EE1} \text{ and } \mathsf{V}_{EE2} > \mathsf{VL1} > \mathsf{VL3} > \mathsf{V}_{EE} \text{ - } \Delta \text{ V, and } \Delta \text{ V} > \mathsf{VL4} > \mathsf{VL2} > \mathsf{V}_{SS1}, \mathsf{V}_{SS2} \mathsf{V}_{SS3} \end{array}$

Power-up and power-down sequences are as follows:

Power-up sequence: $V_{CC} \rightarrow \text{Input} \rightarrow V_{EE1}$, V_{EE2} , V_{EE3} Power-down sequence: V_{EE1} , V_{EE2} , $V_{EE3} \rightarrow \text{Input} \rightarrow V_{CC}$

electrical characteristics over full range of recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
VOH	High-level output voltage	EIO1-EIO4	$V_{CC} = 5 V \pm 10\%,$ $I_{OH} = -0.4 \text{ MA}$	V _{CC} - 0.4		VCC	V
VOL	Low-level output voltage	EIO1-EIO4	$V_{CC} = 5 V \pm 10\%,$ $I_{OL} = -0.4 MA$	VSS		0.4	V
Чн	High-level input current	80CH, BS, D7–D0, DISP OFF, DST, EIO1-EIO4, L/R, M, MODE, SCK	V _{IH} = V _{CC}			5	μΑ
		TEST				500	μΑ
Ι _{ΙL}	Low-level input current	80CH, BS, D7–D0, DISP OFF, DST, EIO1-EIO4, L/R, M, MODE, SCK	V _{IL} = V _{SS}			-5	μΑ
		TEST				-5	μA
z _O	Output impedance	OUT1 to OUT160	$V_{EE} = 14 \text{ V},$ $V_{Ln} = \Delta \text{V},$ $I_{O} = 150 \mu\text{A},$			3	kΩ
ΔZO	Output impedance variance	OUT1 to OUT160	See Note 6		±10%	±30%	
Ц	Input current	VL1, VL2, VL3, VL4	$V_I = V_{EE}, V_{SS}$			±100	μΑ
ICC	Supply current	V _{CC}	1/480 duty operation,			1	mA
IEE	Supply current	V _{EE1} , V _{EE2}	See Note 7			0.5	mA
ICC	Supply current	VCC	1/480 duty operation			5	mA
IEE	Supply current	V _{EE1} , V _{EE2}				2	mA
II(standb	y) Standby current	VCC	See Note 8			500	μA

NOTES: 6. $\Delta Z_O = (1-Xn/Xaverage) \times 100$

Xn = impedance or OUTn, Xaverage = impedance of average OUTn

7. $f_{DST} = 36 \text{ kHz}$, $V_{IH} = V_{CC}$, $V_{IL} = V_{SS}$, and no output load.

8. Voltage level at EIO1 input = V_{CC}



SGLS093 - MARCH 1997

timing requirements over full range of recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
t _C	Cycle time	DST		1		μs
^t w1(L)	Pulse duration, low pulse width	Det		970		ns
^t w1(H)	Pulse duration, high pulse width	1031		30		ns
t _{su1}	Setup time, EIOn valid to DST↓		Soo Figuro 2	100		ns
^t h1	Hold time, EIOn valid to DST \downarrow			30		ns
t _d	Frame delay tolerance time		See Note 10		±300	ns

NOTE 9: This parameter is not production tested.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT
tpd1	1 Propagation delay time, DST \downarrow to EIO1 valid		See Figure 2		110	ns
t _{pd} 2	Propagation delay time, M valid to OUTn valid	C1 - 45 pE	Soo Figuro 2		1.5	μs
t _{pd} 3	Propagation delay time, DST \downarrow to OUTn valid	CL = 45 pr,	See Figure 2		0.7	μs



SGLS093 - MARCH 1997







IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated